Contents

1 Basic Concepts, Quality & Reliability (RAMS) Assurance of Complex Equip. & Systems . 1
1.1 Introduction . . . 1
1.2 Basic Concepts . . . 2
1.2.1 Reliability . . . 2
1.2.2 Failure . . . 3
1.2.3 Failure Rate, *MTTF, MTBF* . . . 4
1.2.4 Maintenance, Maintainability . . . 8
1.2.5 Logistic Support . . . 8
1.2.6 Availability . . . 9
1.2.7 Safety, Risk, Risk Acceptance . . . 9
1.2.8 Quality . . . 11
1.2.9 Cost and System Effectiveness . . . 11
1.2.10 Product Liability . . . 15
1.2.11 Historical Development . . . 16
1.3 Basic Tasks & Rules for Quality & Rel. (RAMS) Assurance of Complex Eq. & Systems . 17
1.3.1 Quality and Reliability (RAMS) Assurance Tasks . . . 17
1.3.2 Basic Quality and Reliability (RAMS) Assurance Rules . . . 19
1.3.3 Elements of a Quality Assurance System. . . . 21
1.3.4 Motivation and Training . . . 24

2 Reliability Analysis During the Design Phase (Nonrepairable Elements up to System Failure) . . 25
2.1 Introduction . . . 25
2.2 Predicted Reliability of Equipment and Systems with Simple Structure . . . 28
2.2.1 Required Function . . . 28
2.2.2 Reliability Block Diagram . . . 28
2.2.3 Operating Conditions at Component Level, Stress Factors . . . 33
2.2.4 Failure Rate of Electronic Components . . . 35
2.2.5 Reliability of One-Item Structures . . . 39
2.2.6 Reliability of Series-Parallel Structures with Independent Elements . . . 41
2.2.6.1 Systems without Redundancy (series models) . . . 41
2.2.6.2 Concept of Redundancy . . . 42
2.2.6.3 Parallel Models . . . 43
2.2.6.4 Series - Parallel Structures with Independent Elements . . . 45
2.2.6.5 Majority Redundancy . . . 49
2.2.7 Part Count Method . . . 51
2.3 Reliability of Systems with Complex Structure . . . 52
2.3.1 Key Item Method . . . 52
2.3.1.1 Bridge Structure . . . 53
2.3.1.2 Rel. Block Diagram in which Elements Appear More than Once . . . 54
2.3.2 Successful Path Method . . . 55
2.3.3 State Space Method . . . 56
2.3.4 Boolean Function Method . . . 57
2.3.5 Parallel Models with Constant Failure Rates and Load Sharing . . . 61
2.3.6 Elements with more than one Failure Mechanism or one Failure Mode . . . 64
2.3.7 Basic Considerations on Fault Tolerant Structures . . . 66
2.4 Reliability Allocation and Optimization . . . 67

2.5 Mechanical Reliability, Drift Failures . . . 68
2.6 Failure Modes Analyses . . . 72
2.7 Reliability Aspects in Design Reviews . . . 77

3 Qualification Tests for Components and Assemblies . . . 81
3.1 Basic Selection Criteria for Electronic Components . . . 81
3.1.1 Environment . . . 82
3.1.2 Performance Parameters . . . 84
3.1.3 Technology . . . 84
3.1.4 Manufacturing Quality . . . 86
3.1.5 Long-Term Behavior of Performance Parameters . . . 86
3.1.6 Reliability . . . 86
3.2 Qualification Tests for Complex Electronic Components . . . 87
3.2.1 Electrical Test of Complex ICs . . . 88
3.2.2 Characterization of Complex ICs . . . 90
3.2.3 Environmental and Special Tests of Complex ICs . . . 92
3.2.4 Reliability Tests . . . 101
3.3 Failure Modes, Mechanisms, and Analysis of Electronic Components . . . 101
3.3.1 Failure Modes of Electronic Components . . . 101
3.3.2 Failure Mechanisms of Electronic Components . . . 102
3.3.3 Failure Analysis of Electronic Components . . . 102
3.3.4 Present VLSI Production-Related Reliability Problems . . . 106
3.4 Qualification Tests for Electronic Assemblies . . . 108

4 Maintainability Analysis . . . 112
4.1 Maintenance, Maintainability . . . 112
4.2 Maintenance Concept . . . 115
4.2.1 Equipment and Systems Partitioning . . . 116
4.2.2 Fault Detection (Recognition) and Localization . . . 116
4.2.3 User Documentation . . . 118
4.2.4 Training of Operation and Maintenance Personnel . . . 119
4.2.5 User Logistic Support . . . 119
4.3 Maintainability Aspects in Design Reviews . . . 121
4.4 Predicted Maintainability . . . 121
4.4.1 Calculation of $MTTR_S$ & MDT_S . . . 121
4.4.2 Calculation of Mean Time to Preventive Maintenance . . . 125
4.5 Basic Models for Spare Parts Provisioning . . . 125
4.5.1 Centralized Logistic Support, Nonrepairable Spare Parts . . . 125
4.5.2 Decentralized Logistic Support, Nonrepairable Spare Parts . . . 129
4.5.3 Repairable Spare Parts . . . 130
4.6 Maintenance Strategies . . . 134
4.6.1 Complete renewal at each maintenance action . . . 134
4.6.2 Block replacement with minimal repair at failure . . . 138
4.6.3 Further considerations on maintenance strategies . . . 139
4.7 Basic Cost Considerations . . . 142

5 Design Guidelines for Reliability, Maintainability, and Software Quality . . . 144
5.1 Design Guidelines for Reliability . . . 144
5.1.1 Derating . . . 144

5.1.2 Cooling . . . 145
5.1.3 Moisture . . . 147
5.1.4 Electromagnetic Compatibility, ESD Protection . . . 148
5.1.5 Components and Assemblies . . . 150
5.1.5.1 Component Selection . . . 150
5.1.5.2 Component Use . . . 150
5.1.5.3 PCB and Assembly Design . . . 151
5.1.5.4 PCB and Assembly Manufacturing . . . 152
5.1.5.5 Storage and Transportation . . . 153
5.1.6 Particular Guidelines for IC Design and Manufacturing . . . 153
5.2 Design Guidelines for Maintainability . . . 154
5.2.1 General Guidelines . . . 154
5.2.2 Testability . . . 155
5.2.3 Connections, Accessibility, Exchangeability . . . 157
5.2.4 Adjustment . . . 158
5.2.5 Human, Ergonomic, and Safety Aspects . . . 158
5.3 Design Guidelines for Software Quality . . . 159
5.3.1 Guidelines for Software Defect Prevention . . . 162
5.3.2 Configuration Management . . . 165
5.3.3 Guidelines for Software Testing . . . 166
5.3.4 Software Quality Growth Models . . . 166

6 Reliability and Availability of Repairable Systems . . . 169
6.1 Introduction, General Assumptions, Conclusions . . . 169
6.2 One-Item Structure . . . 175
6.2.1 One-Item Structure New at Time $t = 0$ . . . 176
6.2.1.1 Reliability Function . . . 176
6.2.1.2 Point Availability . . . 177
6.2.1.3 Average Availability . . . 178
6.2.1.4 Interval Reliability . . . 179
6.2.1.5 Special Kinds of Availability . . . 180
6.2.2 One-Item Structure New at Time $t = 0$ and with Constant Failure Rate λ . . . 183
6.2.3 One-Item Structure with Arbitrary Conditions at $t = 0$ . . . 184
6.2.4 Asymptotic Behavior . . . 185
6.2.5 Steady-State Behavior . . . 187
6.3 Systems without Redundancy . . . 189
6.3.1 Series Structure with Constant Failure and Repair Rates . . . 189
6.3.2 Series Structure with Constant Failure and Arbitrary Repair Rates . . . 192
6.3.3 Series Structure with Arbitrary Failure and Repair Rates . . . 193
6.4 1-out-of-2 Redundancy (Warm, one Repair Crew) . . . 196
6.4.1 1-out-of-2 Redundancy with Constant Failure and Repair Rates . . . 196
6.4.2 1-out-of-2 Redundancy with Constant Failure and Arbitrary Rep. Rates . . . 204
6.4.3 1-out-of-2 Red. with Const. Failure Rate in Reserve State & Arbitr. Rep. Rates . 207
6.5 *k*-out-of-*n* Redundancy (Warm, Identical Elements, one Repair Crew) . . . 213
6.5.1 *k*-out-of-*n* Redundancy with Constant Failure and Repair Rates . . . 214
6.5.2 *k*-out-of-*n* Redundancy with Constant Failure and Arbitrary Repair Rates . . . 218
6.6 Simple Series - Parallel Structures (one Repair Crew) . . . 220
6.7 Approximate Expressions for Large Series - Parallel Structures . . . 226
6.7.1 Introduction . . . 226
6.7.2 Application to a Practical Example . . . 230

6.8 Systems with Complex Structure (one Repair Crew) . . . 238
6.8.1 General Considerations . . . 238
6.8.2 Preventive Maintenance . . . 240
6.8.3 Imperfect Switching . . . 243
6.8.4 Incomplete Coverage . . . 249
6.8.5 Elements with more than two States or one Failure Mode . . . 257
6.8.6 Fault Tolerant Reconfigurable Systems . . . 259
6.8.6.1 Ideal Case . . . 259
6.8.6.2 Time Censored Reconfiguration (Phased-Mission Systems) . . . 259
6.8.6.3 Failure Censored Reconfiguration . . . 266
6.8.6.4 Reward and Frequency / Duration Aspects . . . 270
6.8.7 Systems with Common Cause Failures . . . 271
6.8.8 Basic Considerations on Network-Reliability . . . 275
6.8.9 General Procedure for Modeling Complex Systems . . . 277
6.9 Alternative Investigation Methods . . . 280
6.9.1 Systems with Totally Independent Elements . . . 280
6.9.2 Static and Dynamic Fault Trees . . . 280
6.9.3 Binary Decision Diagrams . . . 283
6.9.4 Event Trees . . . 286
6.9.5 Petri Nets . . . 287
6.9.6 Numerical Reliability and Availability Computation . . . 289
6.9.6.1 Numerical Computation of System's Reliability and Availability . . . 289
6.9.6.2 Monte Carlo Simulations . . . 290
6.9.7 Approximate expressions for Large, Complex Systems . . . 293
6.10 Human Reliability . . . 294
6.11 Risk Management for repairable Systems . . . 299
6.11.1 Introduction . . . 299
6.11.2 Risk Modeling, $S(t)$, *MTTFA* . . . 301
6.11.3 Risk Avoidance and Risk Mitigation . . . 309

7 Statistical Quality Control and Reliability (RAMS) Tests . . . 311
7.1 Statistical Quality Control . . . 311
7.1.1 Estimation of a Defective Probability p . . . 312
7.1.2 Simple Two-sided Sampling Plans for Demonstration of a Def. Probability p . . . 314
7.1.2.1 Simple Two-sided Sampling Plan . . . 315
7.1.2.2 Sequential Test . . . 317
7.1.3 One-sided Sampling Plans for the Demonstration of a Def. Probability p . . . 318
7.2 Statistical Reliability (RAMS) Tests . . . 321
7.2.1 Reliability and Availability Estimation & Demon. for a given (fixed) Mission . . . 321
7.2.2 Availability Estimation & Demonstration for Continuous Operation (steady-state) 323
7.2.2.1 Availability Estimation (Erlangian Failure-Free and/or Repair Times) . . . 323
7.2.2.2 Availability Demonstration (Erlangian Failure-Free and/or Repair Times) . 325
7.2.2.3 Further Availability Evaluation Methods for Continuous Operation . . . 326
7.2.3 Estimation and Demonstration of a Const. Failure Rate λ (or of $MTBF = 1/\lambda$) . . . 328
7.2.3.1 Estimation of a Constant Failure Rate λ . . . 330
7.2.3.2 Simple Two-sided Test for the Demonstration of λ . . . 332
7.2.3.3 Simple One-sided Test for the Demonstration of λ . . . 336
7.3 Estimation and Demonstration of an *MTTR* . . . 337
7.3.1 Estimation of an *MTTR* . . . 337
7.3.2 Demonstration of an *MTTR* . . . 339
7.4 Accelerated Testing . . . 341

7.5 Goodness-of-fit Tests . . . 346
7.5.1 Kolmogorov-Smirnov Test . . . 346
7.5.2 Chi-square Test . . . 350
7.6 Statistical Analysis of General Reliability Data . . . 353
7.6.1 General considerations . . . 353
7.6.2 Tests for Nonhomogeneous Poisson Processes . . . 355
7.6.3 Trend Tests . . . 357
7.6.3.1 Tests of a HPP versus a NHPP with increasing intensity . . . 357
7.6.3.2 Tests of a HPP versus a NHPP with decreasing intensity . . . 360
7.6.3.3 Heuristic Tests to distinguish between HPP and Monotonic Trend . . . 361
7.7 Reliability Growth . . . 363

8 Quality & Reliability Assurance During the Production Phase (Basic Considerations) . . . 369
8.1 Basic Activities . . . 369
8.2 Testing and Screening of Electronic Components . . . 370
8.2.1 Testing of Electronic Components . . . 370
8.2.2 Screening of Electronic Components . . . 371
8.3 Testing and Screening of Electronic Assemblies . . . 374
8.4 Test and Screening Strategies, Economic Aspects . . . 376
8.4.1 Basic Considerations . . . 376
8.4.2 Quality Cost Optimization at Incoming Inspection Level . . . 379
8.4.3 Procedure to handle first deliveries . . . 384

Appendices *(A1 - A11)*

A1 Terms and Definitions . . . 385

A2 Quality and Reliability (RAMS) Standards, Story of Reliability Engineering . . . 401
A2.1 Introduction . . . 401
A2.2 General Requirements in the Industrial Field . . . 402
A2.3 Requirements in the Aerospace, Railway, Defense, and Nuclear Fields . . . 404
A2.4 A Skillful, Allegorical Story of Reliability . . . 405

A3 Definition and Realization of Quality & Reliability (RAMS) Requirements . . . 407
A3.1 Definition of Quality and Reliability (RAMS) Requirements . . . 407
A3.2 Realization of Quality & Reliability (RAMS) Requirements for Complex Eq. & Syst. . . . 409
A3.3 Elements of a Quality and Reliability (RAMS) Assurance Program . . . 414
A3.3.1 Project Organization, Planning, and Scheduling . . . 414
A3.3.2 Quality and Reliability (RAMS) Requirements . . . 415
A3.3.3 Reliability, Maintainability, and Safety Analyses . . . 415
A3.3.4 Selection & Qualification of Components, Materials, Manuf. Processes. . . . 416
A3.3.5 Software Quality Assurance . . . 416
A3.3.6 Configuration Management . . . 417
A3.3.7 Quality Tests . . . 418
A3.3.8 Quality Data Reporting System . . . 420

A4 Checklists for Design Reviews . . . 421
A4.1 System Design Review . . . 421
A4.2 Preliminary Design Reviews . . . 422
A4.3 Critical Design Review (System Level) . . . 425

A5 Requirements for a Quality Data Reporting System . . . 426

A6 Basic Probability Theory 429
A6.1 Field of Events 429
A6.2 Concept of Probability 431
A6.3 Conditional Probability, Independence 434
A6.4 Fundamental Rules of Probability Theory 435
A6.4.1 Addition Theorem for Mutually Exclusive Events 435
A6.4.2 Multiplication Theorem for Two Independent Events 436
A6.4.3 Multiplication Theorem for Arbitrary Events 437
A6.4.4 Addition Theorem for Arbitrary Events 437
A6.4.5 Theorem of Total Probability 438
A6.5 Random Variables, Distribution Functions 439
A6.6 Numerical Parameters of Random Variables 445
A6.6.1 Expected Value (Mean) 445
A6.6.2 Variance 448
A6.6.3 Modal Value, Quantile, Median 450
A6.7 Multidimensional Random Variables, Conditional Distributions 450
A6.8 Numerical Parameters of Random Vectors 452
A6.8.1 Covariance Matrix, Correlation Coefficient 453
A6.8.2 Further Properties of Expected Value and Variance 454
A6.9 Distribution of the Sum of Indep. Positive Random Variables and of $\tau_{\min}$, $\tau_{\max}$ . . 454
A6.10 Distribution Functions used in Reliability Analysis 457
A6.10.1 Exponential Distribution 457
A6.10.2 Weibull Distribution 458
A6.10.3 Gamma Distribution, Erlangian Distribution, and χ^2–Distribution . . 460
A6.10.4 Normal Distribution 462
A6.10.5 Lognormal Distribution 463
A6.10.6 Uniform Distribution 465
A6.10.7 Binomial Distribution 465
A6.10.8 Poisson Distribution 467
A6.10.9 Geometric Distribution 469
A6.10.10 Hypergeometric Distribution 470
A6.11 Limit Theorems 470
A6.11.1 Laws of Large Numbers 471
A6.11.2 Central Limit Theorem 472

A7 Basic Stochastic-Processes Theory 476
A7.1 Introduction 476
A7.2 Renewal Processes 479
A7.2.1 Renewal Function, Renewal Density 481
A7.2.2 Recurrence Times 484
A7.2.3 Asymptotic Behavior 485
A7.2.4 Stationary Renewal Processes 487
A7.2.5 Homogeneous Poisson Processes (HPP) 488
A7.3 Alternating Renewal Processes 490
A7.4 Regenerative Processes with a Finite Number of States 494
A7.5 Markov Processes with a Finite Number of States 496
A7.5.1 Markov Chains with a Finite Number of States 496
A7.5.2 Markov Processes with a Finite Number of States 498
A7.5.3 State Probabilities and Stay Times in a Given Class of States 507
A7.5.3.1 Method of Differential Equations 507
A7.5.3.2 Method of Integral Equations 511
A7.5.3.3 Stationary State and Asymptotic Behavior 512

A7.5.4 Frequency / Duration and Reward Aspects . . . 514
A7.5.4.1 Frequency / Duration . . . 514
A7.5.4.2 Reward . . . 516
A7.5.5 Birth and Death Process . . . 517
A7.6 Semi-Markov Processes with a Finite Number of States . . . 521
A7.7 Semi-regenerative Processes with a Finite Number of States . . . 526
A7.8 Nonregenerative Stochastic Processes with a Countable Number of States . . . 531
A7.8.1 General Considerations . . . 531
A7.8.2 Nonhomogeneous Poisson Processes (NHPP) . . . 532
A7.8.3 Superimposed Renewal Processes . . . 536
A7.8.4 Cumulative Processes . . . 537
A7.8.5 General Point Processes . . . 539

A8 Basic Mathematical Statistics . . . 541
A8.1 Empirical Methods . . . 541
A8.1.1 Empirical Distribution Function . . . 542
A8.1.2 Empirical Moments and Quantiles . . . 544
A8.1.3 Further Applications of the Empirical Distribution Function . . . 545
A8.2 Parameter Estimation . . . 549
A8.2.1 Point Estimation . . . 549
A8.2.2 Interval Estimation . . . 554
A8.2.2.1 Estimation of an Unknown Probability p . . . 554
A8.2.2.2 Estimation of Param. λ for Exp. Distrib.: Fixed T, instant. repl. . . 558
A8.2.2.3 Estimation of Param. λ for Exp. Distrib.: Fixed n, no repl. . . . 559
A8.2.2.4 Availability Estimation (Erlangian Failure-Free and/or Repair Times) 561
A8.3 Testing Statistical Hypotheses . . . 563
A8.3.1 Testing an Unknown Probability p . . . 564
A8.3.1.1 Simple Two-sided Sampling Plan . . . 565
A8.3.1.2 Sequential Test . . . 566
A8.3.1.3 Simple One-sided Sampling Plan . . . 567
A8.3.1.4 Availability Demonstr. (Erlangian Failure-Free and/or Rep. Times) . . 569
A8.3.2 Goodness-of-fit Tests for Completely Specified $F_0(t)$ . . . 571
A8.3.3 Goodness-of-fit Tests for $F_0(t)$ with Unknown Parameters . . . 574

A9 Tables and Charts . . . 577
A9.1 Standard Normal Distribution . . . 577
A9.2 χ^2-Distribution (Chi-Square Distribution) . . . 578
A9.3 t-Distribution (Student distribution) . . . 579
A9.4 F-Distribution (Fisher distribution) . . . 580
A9.5 Table for the Kolmogorov-Smirnov Test . . . 581
A9.6 Gamma Function . . . 582
A9.7 Laplace Transform . . . 583
A9.8 Probability Charts (Probability Plot Papers) . . . 585
A9.8.1 Lognormal Probability Chart . . . 585
A9.8.2 Weibull Probability Chart . . . 586
A9.8.3 Normal Probability Chart . . . 587

A10 Basic Technological Component's Properties . . . 588

A11 Problems for Homework . . . 592

Acronyms . . . 600
References . . . 601
Index . . . 627